

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Naoki NAKAMURA

Application No.: New US Patent Application

Filed: March 19, 2002

Docket No.: 112318

For: SUBMERGED SAMPLE OBSERVATION APPARATUS AND METHOD



INFORMATION DISCLOSURE STATEMENT

Director of the U.S. Patent and Trademark Office
Washington, D.C. 20231

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. A concise explanation of the relevance of the non-English language references appears in the Appendix attached hereto.
- ☒ 3. English-language Abstracts of the non-English language references are attached hereto.

Respectfully submitted,

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APPENDIX

Information List (Form1)

The following is a List of References provided by Applicant.
Please file an Information Disclosure Statement using this Information.

Document Number	Publication Date	Brief Explanation or Page(s) & Line(s) of Related Part(s)
JP-A-9-54098	February 25, 1997	A sample is immersed in a liquid while the surface to be observed of the sample faces down. Illuminating light is applied from below.
JP-A-10-132829	May 22, 1998	The cantilever is covered with an insulator excluding at the probe tip part.